L Number	Hits	Search Text	DB	Time stamp
-	1148	716/19	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 11:48
-	758	716/21	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 11:48
-	11	(716/19).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 16:46
-	15	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:30
-	1	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:33
-	2	(716/$).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:34
-	13	(mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:35
-	2	(mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:11
-	2	(mask or reticle) and (((electron adj beam) or EB) same data) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:13
-	3	(mask or reticle) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:20
-	3	(mask or reticle) and ((data adj (translation or conversion) adj error))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:26
-	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj error))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:27

-	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj (error or mistake)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:29
-	2	CAD and ((data adj (translation or conversion) adj (error or mistake)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:30
-	0	(beam adj lithograph) same (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:49
-	0	(beam adj lithograph) and (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:47
-	7	(beam adj lithography) same (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:50
-	30	(beam adj lithography) and (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:38
-	21	(beam adj lithography) and (inspection adj method) and (quality or contrast)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:40
-	2	(beam adj lithography) and ((inspection adj method) same (quality or contrast))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:42
-	1	(mask or reticle) and ((data adj verification) same (coordinate adj data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:18
-	4	(mask or reticle) and ((data adj verification) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:36
-	38	(mask or reticle) and ((data adj (check$ or verification)) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:52
-	9	(mask or reticle) and (electron adj beam) and ((data adj (check$ or verification)) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:02

C:\APPS\east\workspaces\CASE208.wsp

-	1	(mask or reticle) and (electron adj beam) and ((data adj (check$ or verification)) same ((two adj dimension$) adj (coordinate)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:29
-	0	(mask or reticle) and (electron adj beam) and ((pattern adj (check$ or verification)) same ((two adj dimension$) adj (coordinate)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:30
-	1	(mask or reticle) and (electron adj beam) and ((check$ or verification) same ((two adj dimension$) adj (coordinate)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:34
-	64	(mask or reticle) and (electron adj beam) and (pattern adj (check$ or verification))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:34

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore RELEASE 1.8

Welcome
United States Patent and Trademark Office

IEEE Xplore®
1 Million Documents
1 Million Users

» **Search Results**

Help   FAQ   Terms   IEEE Peer Review   **Quick Links** ▼

Your search matched **0** of **1074479** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or entering a new one in the text box.

(reticle) <and> (electron beam) <and> (data verifica| **Search**

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

Results:
No documents matched your query.

Welcome to IEEE Xplore
- Home
- What Can I Access?
- Log-out

Tables of Contents
- Journals & Magazines
- Conference Proceedings
- Standards

Search
- By Author
- Basic
- Advanced

Member Services
- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Business
- Access the IEEE Enterprise File Cabinet

Print Format

9-27-04

h   ieee   e eee   g e ch e ch e   e   c e   e   e c e   c

◈IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore
RELEASE 1.8

Welcome
United States Patent and Trademark Office

IEEE Xplore®
1 Million Documents
1 Million Users

» Search Results

Help   FAQ   Terms   IEEE Peer Review   Quick Links

Welcome to IEEE Xplore

○ Home
○ What Can
   I Access?
○ Log-out

Tables of Contents

○ Journals
   & Magazines
○ Conference
   Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE
   Web Account

○ Access the
   IEEE Member
   Digital Library

○ Access the
   IEEE Enterprise
   File Cabinet

Your search matched **0** of **1074479** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or entering a new one in the text box.

(mask) <and> (electron beam) <and> (data verificati   Search

☐ Check to search within this result set ·

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

Results:
No documents matched your query.

🖨 Print Format

9-27-04

h   ieee   e eee   g e ch e ch e   e   e   e ec   be

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.8

Welcome
United States Patent and Trademark Office

IEEE Xplore®
1 Million Documents
1 Million Users

» Search Results

Help   FAQ   Terms   IEEE Peer Review

Quick Links   ▼

Welcome to IEEE Xplore

○ Home
○ What Can I Access?
○ Log-out

Tables of Contents

○ Journals & Magazines
○ Conference Proceedings
○ Standards

Search

○ By Author
○ Basic
○ Advanced

Member Services

○ Join IEEE
○ Establish IEEE Web Account
○ Access the IEEE Member Digital Library

IEEE Enterprise

○ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1074479** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:
You may refine your search by editing the current search expression or entering a new one in the text box.

(mask writing system) <and> (electron beam)   [Search]

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

Results:
No documents matched your query.

🖨 Print Format

9-27-04

h   ieee   e eee   g e ch e ch e   e c e   e ec e   c